Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/654,770	PARK ET AL.
Examiner	Art Unit
Binh X. Tran	1765

SEARCHED					
Class	Subclass	Date	Examiner		
438	696	8/22/2005	ВТ		
438	697	8/22/2005	ВТ		
438	700	8/22/2005	ВТ		
438 .	710	8/22/2005	ВТ		
438	718	8/22/2005	ВТ		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	1.				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Update search using USPAT, USPG- PUB, JPO, EPO, DERWENT databases	8/22/2005	вт		
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